

ISO 20339:2017-03 (E)

Non-destructive testing - Equipment for eddy current examination - Array probe characteristics and verification

Contents		Page
Foreword		v
1	Scope	1
2	Normative references	1
3	Terms and definitions	1
4	Probe and interconnecting elements characteristics	2
4.1	General characteristics	2
4.1.1	Application	2
4.1.2	Probe types	2
4.1.3	Interconnecting elements	2
4.1.4	Physical characteristics	2
4.1.5	Safety	3
4.1.6	Environmental conditions	3
4.2	Electrical characteristics	3
4.3	Functional characteristics	3
5	Verification	4
5.1	Level of verifications	4
5.2	Characteristics to be verified	4
6	Measurement of electrical and functional characteristics of an array probe	5
6.1	Electrical characteristics	5
6.1.1	General	5
6.1.2	Measurement conditions	5
6.1.3	Impedance of coil elements	5
6.1.4	Impedance of a pattern	5
6.1.5	Channel assignment -- Sequencing	6
6.1.6	Cross-talk	6
6.2	Functional characteristics	6
6.2.1	General	6
6.2.2	Measurement conditions	6
7	Surface array probes	8
7.1	Reference blocks	8
7.2	Probe motion	9
7.3	Reference signal -- Normalization	9
7.4	Edge effect (measurable in the case of simple geometry, e.g. metal sheets, disks)	10
7.5	Response to a slot	11
7.6	Response to a hole	12
7.7	Length of coverage	12
7.8	Variation in sensitivity between patterns	12
7.9	Minimum slot length for constant probe response	13
7.10	Lift-off effect	13
7.11	Effect of probe clearance on slot response	13
7.12	Effective depth of detection of a sub-surface slot	14
7.13	Resolution	14
7.14	Defective element or pattern	14

8	Coaxial array probes	14
8.1	General conditions	14
8.2	Reference blocks	14
8.3	Reference signal	16
8.4	Absence of defective elements	17
8.5	Position mark of the probe (mainly for positioning)	17
8.6	End effect	17
8.7	Length of coverage	17
8.8	Homogeneity of axial response	18
8.9	Eccentricity effect	19
8.10	Fill effect	19
8.11	Effective depth of penetration	19
8.12	Effective depth of detection under ligament	19
9	Influence of interconnecting elements	19
	Annex A (informative) Simulation of surface probe resolution	20